

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		2838	Page 1 of 1
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,550,290	04-2003	Shimakage et al.	68/12.04
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	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP04-359890	12-1992	JAPAN	Makino Yasuhiro	
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NON-PATENT DOCUMENTS

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	V	Mitsubishi Semiconductor Power Modules MOS, Application Note, Using Intelligent Power Modules, September 1998, pages 1-31.
	W	Mitsubishi Semiconductor Power Modules MOS, Application Note, General Considerations for IGBT and Intelligent Power Modules, September 1998, pages 1-18.
	X	Patent Abstracts of Japan, Patent Abstract of JP04-359890, 14.12.1992, pages 1-2.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.